

Maximum Ratings @T_A = 25°C unless otherwise specified

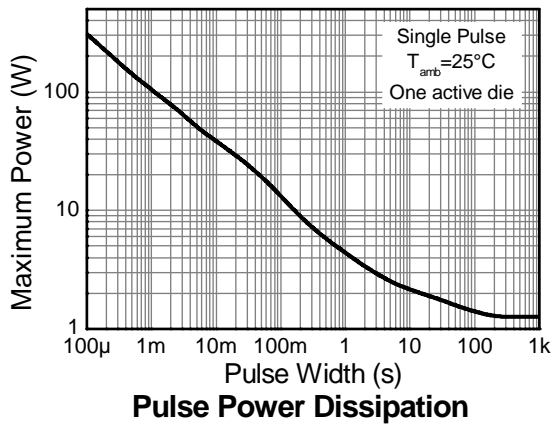
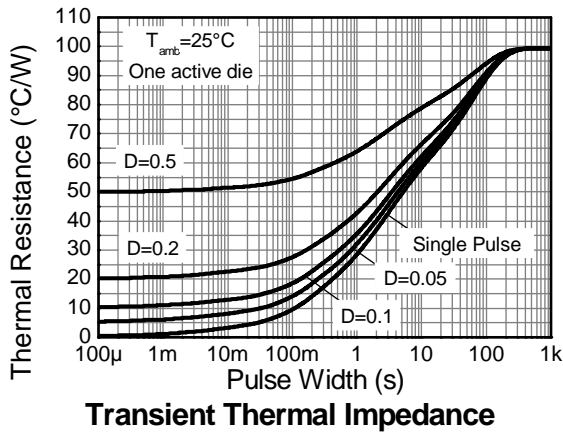
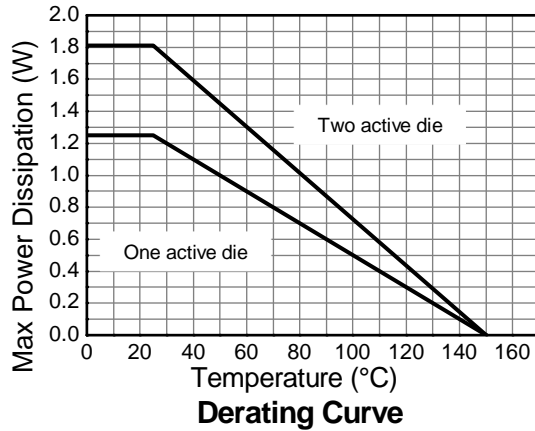
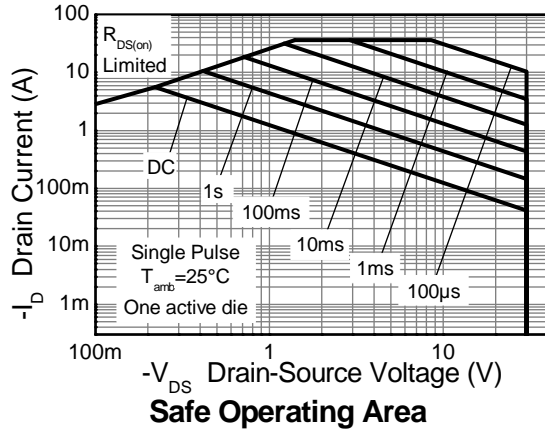
Characteristic			Symbol	Value	Unit
Drain-Source voltage			V _{DSS}	-30	V
Gate-Source voltage			V _{GS}	±20	V
Continuous Drain current	V _{GS} = -10V	(Notes 3 & 5)	I _D	-7.3	A
		T _A = 70°C (Notes 3 & 5)		-5.9	
		(Notes 2 & 5)		-5.7	
		(Note 7)		-8.3	
Pulsed Drain current			I _{DM}	-36	A
Continuous Source current (Body diode)			I _S	-3.5	A
Pulsed Source current (Body diode)			I _{SM}	-36	A

Thermal Characteristics @T_A = 25°C unless otherwise specified

Characteristic		Symbol	Value	Unit
Power dissipation Linear derating factor	(Notes 2 & 5)	P _D	1.25	W mW/°C
			10.0	
	(Notes 2 & 6)		1.81	
			14	
	(Notes 3 & 5)		2.1	
			17	
Thermal Resistance, Junction to Ambient	(Notes 2 & 5)	R _{θJA}	100	°C/W
	(Notes 2 & 6)		70	
	(Notes 3 & 5)		60	
Thermal Resistance, Junction to Lead	(Notes 2 & 7)	R _{θJL}	46	
Operating and storage temperature range		T _J , T _{STG}	-55 to +150	°C

- Notes:
2. For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
 3. For a dual device surface mounted on FR4 PCB measured at t ≤ 10 sec.
 4. Repetitive rating on 25mm X 25mm FR4 PCB, pulsed with D = 0.02 and pulse width 300µs – pulse width limited by maximum junction temperature.
 5. For a dual device with one active die.
 6. For a device with two active die running at equal power.
 7. Thermal resistance from junction to solder-point (at the end of the drain lead).

Thermal Characteristics

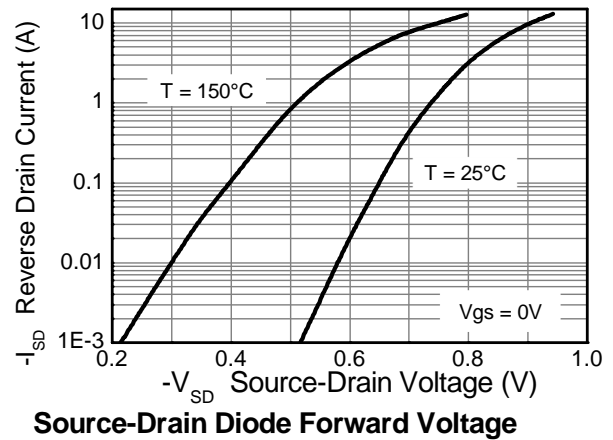
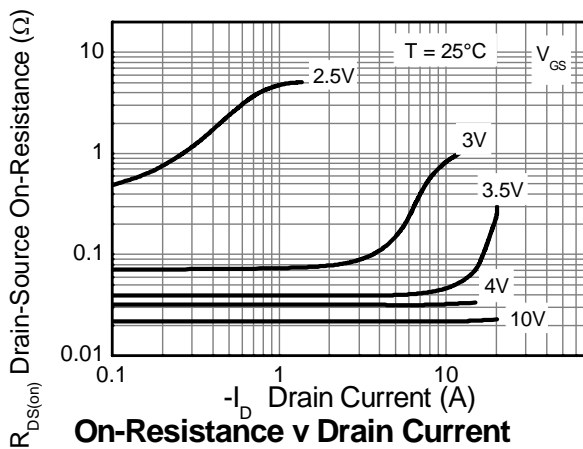
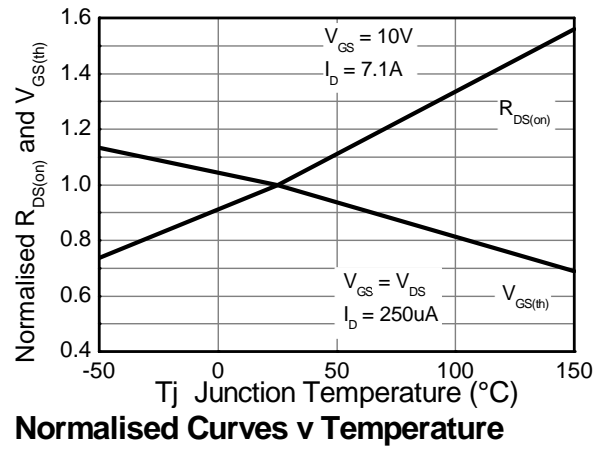
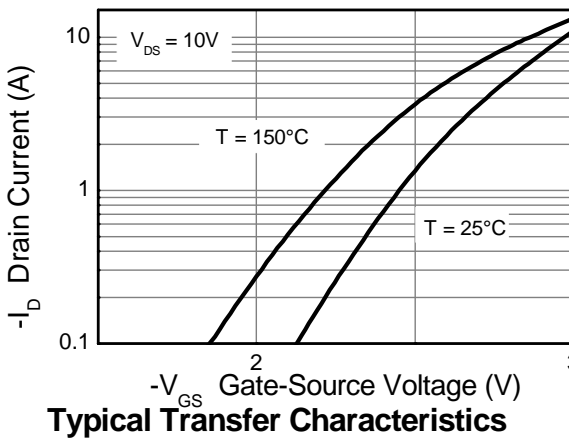
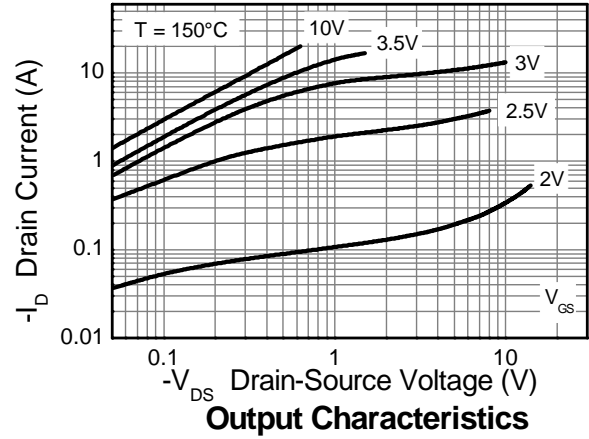
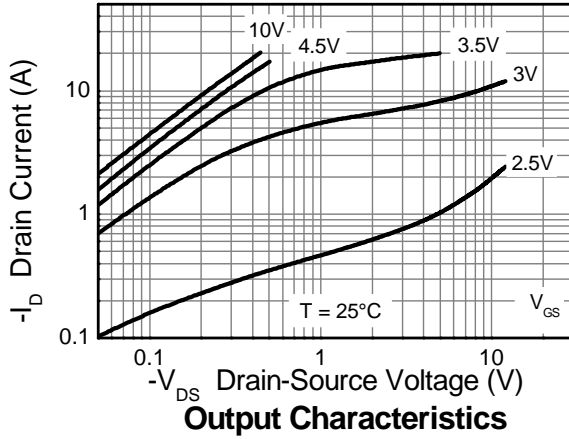


Electrical Characteristics @ $T_A = 25^\circ\text{C}$ unless otherwise specified

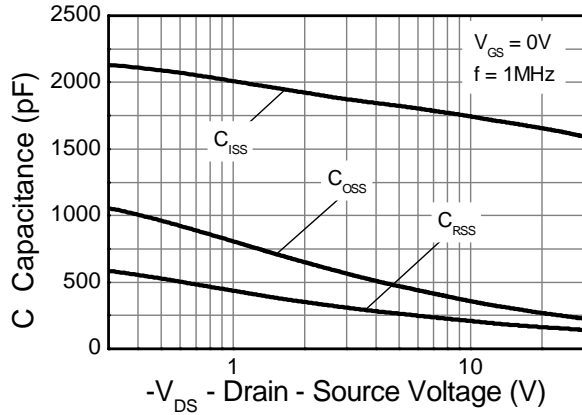
Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV_{DSS}	-30	—	—	V	$I_D = -250\mu\text{A}, V_{GS} = 0\text{V}$
Zero Gate Voltage Drain Current	I_{DSS}	—	—	-0.5	μA	$V_{DS} = -30\text{V}, V_{GS} = 0\text{V}$
Gate-Source Leakage	I_{GSS}	—	—	± 100	nA	$V_{GS} = \pm 20\text{V}, V_{DS} = 0\text{V}$
ON CHARACTERISTICS						
Gate Threshold Voltage	$V_{GS(th)}$	-1.0	—	-3.0	V	$I_D = -250\mu\text{A}, V_{DS} = V_{GS}$
Static Drain-Source On-Resistance (Note 8)	$R_{DS(on)}$	—	—	25	m Ω	$V_{GS} = -10\text{V}, I_D = -7.1\text{A}$
			—	41		$V_{GS} = -4.5\text{V}, I_D = -5.5\text{A}$
Forward Transconductance (Notes 8 & 9)	g_{fs}	—	18.6	—	S	$V_{DS} = -15\text{V}, I_D = -7.1\text{A}$
Diode Forward Voltage (Note 8)	V_{SD}	—	-0.8	-1.2	V	$I_S = -1.7\text{A}, V_{GS} = 0\text{V}$
Reverse recovery time (Note 9)	t_{rr}	—	16.2	—	ns	$I_S = -2.2\text{A}, di/dt = 100\text{A}/\mu\text{s}$
Reverse recovery charge (Note 9)	Q_{rr}	—	10	—	nC	
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	C_{iss}	—	1678	—	pF	$V_{DS} = -15\text{V}, V_{GS} = 0\text{V}$ $f = 1\text{MHz}$
Output Capacitance	C_{oss}	—	303	—	pF	
Reverse Transfer Capacitance	C_{rss}	—	178	—	pF	
Total Gate Charge (Note 10)	Q_g	—	31.6	—	nC	$V_{GS} = -10\text{V}, V_{DS} = -15\text{V},$ $I_D = -7.1\text{A}$
Gate-Source Charge (Note 10)	Q_{gs}	—	4.3	—	nC	
Gate-Drain Charge (Note 10)	Q_{gd}	—	6.2	—	nC	
Turn-On Delay Time (Note 10)	$t_{D(on)}$	—	3.5	—	ns	$V_{DD} = -15\text{V}, V_{GS} = -10\text{V}$ $I_D = -1\text{A}, R_G \cong 6.0\Omega$
Turn-On Rise Time (Note 10)	t_r	—	4.9	—	ns	
Turn-Off Delay Time (Note 10)	$t_{D(off)}$	—	44	—	ns	
Turn-Off Fall Time (Note 10)	t_f	—	28	—	ns	

- Notes:
8. Measured under pulsed conditions. Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$
 9. For design aid only, not subject to production testing.
 10. Switching characteristics are independent of operating junction temperatures.

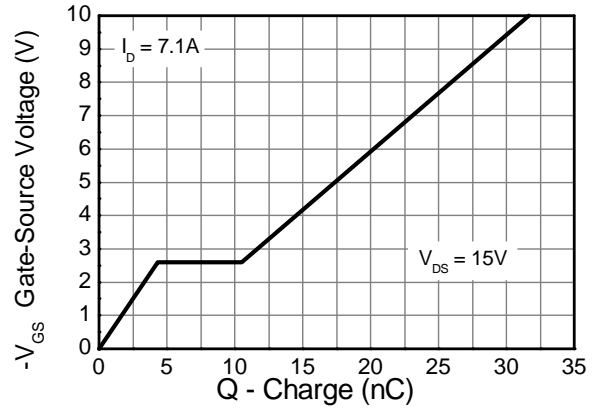
Typical Characteristics



Typical Characteristics - continued

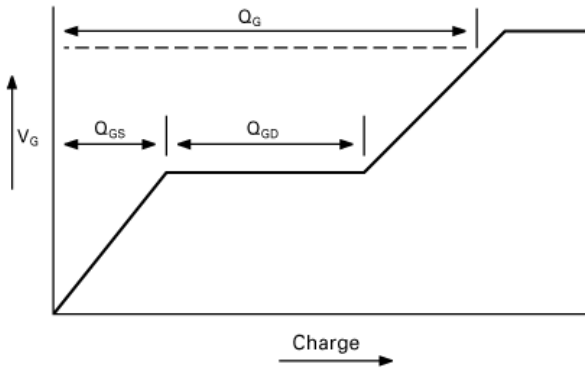


Capacitance v Drain-Source Voltage

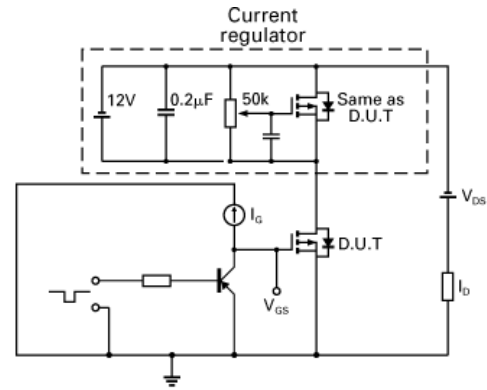


Gate-Source Voltage v Gate Charge

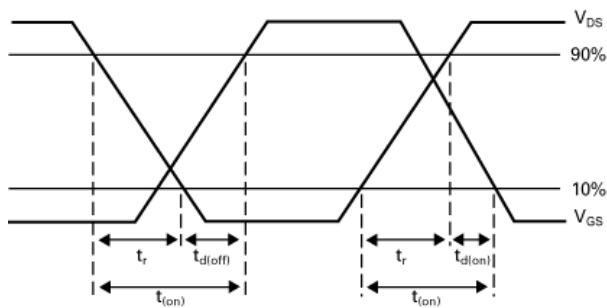
Test Circuits



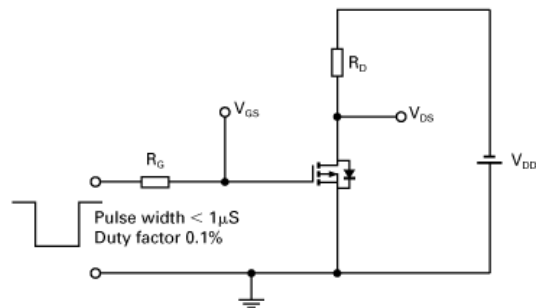
Basic gate charge waveform



Gate charge test circuit

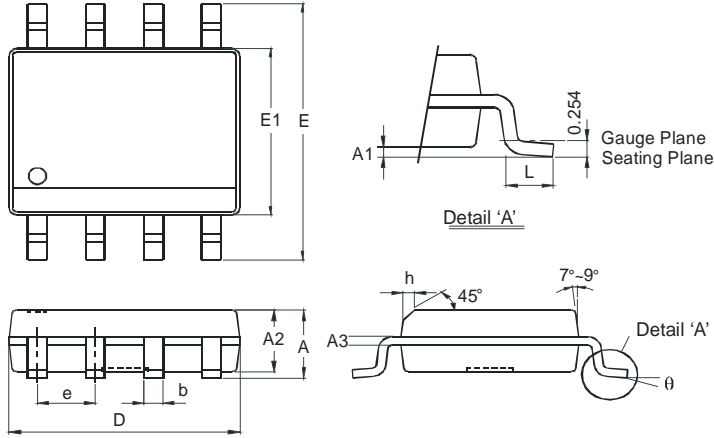


Switching time waveforms



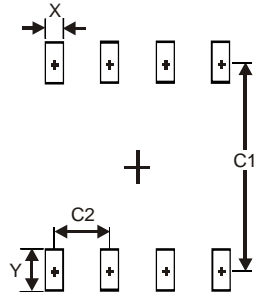
Switching time test circuit

Package Outline Dimensions



SO-8		
Dim	Min	Max
A	-	1.75
A1	0.10	0.20
A2	1.30	1.50
A3	0.15	0.25
b	0.3	0.5
D	4.85	4.95
E	5.90	6.10
E1	3.85	3.95
e	1.27 Typ	
h	-	0.35
L	0.62	0.82
θ	0°	8°
All Dimensions in mm		

Suggested Pad Layout



Dimensions	Value (in mm)
X	0.60
Y	1.55
C1	5.4
C2	1.27

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